

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KLEIN ET AL.	
		Examiner Christopher B. Shin	Art Unit 2182	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,574,717	06-2003	Ngai et al.	711/147
*	B	US-6,871,263	03-2005	Dandrea, Robert G.	711/114
*	C	US-5,873,101	02-1999	Klein, Jonathan D.	707/204
*	D	US-6,973,549	12-2005	Testardi, Richard	711/150
*	E	US-6,487,561	11-2002	Ofek et al.	707/204
*	F	US-6,804,627	10-2004	Marokhovsky et al.	702/182
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.